Search Notes



Application/Control No.	Applicate Reexam
40550047	DADKE

10552947

Examiner

Nguyen, Hiep

Applicant(s)/Patent Under Reexamination

BARKER, RICHARD J.

**Art Unit** 

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## **SEARCH NOTES**

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Search Notes	Date	Examiner
EAST (see attachment)	09-18-07	'Hn

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner